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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
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EXAMINER	
SHAPIRO, LEONID	
ART UNIT	**PAPER NUMBER**
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Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No.	Applicant(s)	
	09/938,614	KAGEYAMA ET AL.	
	Examiner	Art Unit	
	Leonid Shapiro	2673	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

1)☒ Responsive to communication(s) filed on *01 January 1952*.

2a)☐ This action is **FINAL**. 2b)☒ This action is non-final.

3)☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

4)☐ Claim(s) _____ is/are pending in the application.

4a) Of the above claim(s) _____ is/are withdrawn from consideration.

5)☐ Claim(s) _____ is/are allowed.

6)☒ Claim(s) *1-52* is/are rejected.

7)☐ Claim(s) _____ is/are objected to.

8)☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

9)☐ The specification is objected to by the Examiner.

10)☐ The drawing(s) filed on _____ is/are: a)☐ accepted or b)☐ objected to by the Examiner.

Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).

Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).

11)☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

12)☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).

a)☐ All b)☐ Some * c)☐ None of:

1.☐ Certified copies of the priority documents have been received.

2.☐ Certified copies of the priority documents have been received in Application No. _____.

3.☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

1) ☐ Notice of References Cited (PTO-892)
2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3) ☐ Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date _____.
4) ☐ Interview Summary (PTO-413) Paper No(s)/Mail Date. _____ .
5) ☐ Notice of Informal Patent Application (PTO-152)
6) ☐ Other: _____.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

> (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

1. Claims 1-16, 25-44 and 49-52 are rejected under 35 U.S.C. 103(a) as being unpatentable over Proebsting (US Patent No. 5,952,948) in view Akiyama et al. (US Patent No. 6,201,523 B1).

As to claim 1, Proebsting teaches a drive circuit, comprising: a plurality of digital-to-analog conversion circuit (See Fig. 1, items 106-1 to 106-n, See Col. 1, lines 38-49) each of which selects one of difference reference voltages (See Fig. 5, items 404-409, Col. 4, Lines 1-30) corresponding to a digital gradation signal (See Fig. 4, item 410, Col. 4, Lines 30-34); and wherein the digital-to analog conversion circuit between the selected reference voltage and the output terminal of the digital-to analog conversion circuit includes a variable resistor circuit with a resistance value corresponding to a digital gradation signal lines (See Fig. 4-5, items 404,406,408,410, from Col. 4, Line 1 to Col.5, Line 20); wherein the sampling circuit comprises a plurality of switches each of which has an approximate same resistance value (See Fig. 4, items 404, 406, 408,Col. 4, Lines 26-30); wherein a divided voltage point of selected reference voltages is generated by a series resistance comprising a resistance value of the variable

resistance circuit and resistance value of switches constituting the sampling circuit (See Fig. 4, items 404, 406, r, 408, Col. 4, Lines 1-34).

Proebsting does not teach a sampling circuit which selectively connects each output terminal of two of the digital-to-analog conversion circuit to signal lines.

Akiyama et al. teaches a sampling circuit which connects each output terminal of two of the digital-to-analog conversion circuit to signal lines (See Fig. 8, items 113, 123, Col. 9, Lines 26-36); wherein the sampling circuit outputs a predetermined voltage by connecting an output voltage terminal of the plurality of digital-to-analog conversion circuits to one of signal lines (See Fig. 8, items 113, 123, Col. 9, Lines 26-36).

It would have been obvious to one of ordinary skill in the art at the time of invention to add a sampling circuit as shown by Akiyama et al. to the Proebsting apparatus in order to lower cost by employing parts of first and second DAC's commonly (See Col. 2, Lines 33-36 in Akiyama et al. reference).

As to claim 2, Proebsting teaches a drive circuit, comprising: a plurality of digital-to-analog conversion circuit (See Fig. 1, items 106-1 to 106-n, See Col. 1, lines 38-49) each of which selects one of difference reference voltages (See Fig. 5, items 404-409, Col. 4, Lines 1-30) corresponding to a digital gradation signal (See Fig. 4, item 410, Col. 4, Lines 30-34; a plurality of switching element groups including a plurality of switching elements which are connected to each other in parallel, wherein each of which has a difference resistance value in active, connects to a corresponding output terminal of the digital-to-analog conversion circuit and is controlled according to a digital gradation signal (See Fig. 4-5, items 404,406,408,410, from Col. 4, Line 1 to Col.5, Line 20);

wherein the sampling circuit comprises a plurality of switches each of which has an approximate same resistance value (See Fig. 4, items 404, 406, 408,Col. 4, Lines 26-30); wherein a divided voltage point of selected reference voltages is generated by a series resistance comprising a resistance value of the variable resistance circuit and resistance value of switches constituting the sampling circuit (See Fig. 4, items 404, 406, r, 408, Col. 4, Lines 1-34).

Proebsting does not teach a sampling circuit which selectively connects each output terminal of two of the digital-to-analog conversion circuit to signal lines and wherein the sampling circuit outputs a predetermined voltage by connecting an output voltage terminal of the plurality of digital-to-analog conversion circuits to one of signal lines.

Akiyama et al. teaches a sampling circuit which connects each output terminal of two of the digital-to-analog conversion circuit to signal lines (See Fig. 8, items 113, 123, Col. 9, Lines 26-36); wherein the sampling circuit outputs a predetermined voltage by connecting an output voltage terminal of the plurality of digital-to-analog conversion circuits to one of signal lines (See Fig. 8, items 113, 123, Col. 9, Lines 26-36).

It would have been obvious to one of ordinary skill in the art at the time of invention to add a sampling circuit as shown by Akiyama et al. to the Proebsting apparatus in order to lower cost by employing parts of first and second DAC's commonly (See Col. 2, Lines 33-36 in Akiyama et al. reference).

As to claim 3, Proebsting teaches a drive circuit, comprising: a plurality of digital-to-analog conversion circuit (See Fig. 1, items 106-1 to 106-n, See Col. 1, lines 38-49)

each of which connects one of difference reference voltages (See Fig. 5, items 404-409, Col. 4, Lines 1-30) corresponding to a digital gradation signal (See Fig. 4, item 410, Col. 4, Lines 30-34; wherein each output terminal of the digital-to analog conversion circuits connects to a corresponding variable resistor circuit with a resistance value corresponding to a digital gradation circuit (See Fig. 4-5, items 404,406,408,410, from Col. 4, Line 1 to Col.5, Line 20); wherein the sampling circuit comprises a plurality of switches each of which has an approximate same resistance value (See Fig. 4, items 404, 406, 408,Col. 4, Lines 26-30); wherein a divided voltage point of selected reference voltages is generated by a series resistance comprising a resistance value of the variable resistance circuit and resistance value of switches constituting the sampling circuit (See Fig. 4, items 404, 406, r, 408, Col. 4, Lines 1-34).

Proebsting does not teach a sampling circuit which selectively connects each output terminal of two of a plurality of variable resistor circuits to one of a plurality to signal lines and wherein the sampling circuit outputs a predetermined voltage by connecting an output voltage terminal of the plurality of digital-to-analog conversion circuits to one of signal lines.

Akiyama et al. teaches a sampling circuit which connects each output terminal of two of the digital-to-analog conversion circuit to signal lines (See Fig. 8, items 113, 123, Col. 9, Lines 26-36); wherein the sampling circuit outputs a predetermined voltage by connecting an output voltage terminal of the plurality of digital-to-analog conversion circuits to one of signal lines (See Fig. 8, items 113, 123, Col. 9, Lines 26-36).

It would have been obvious to one of ordinary skill in the art at the time of invention to add a sampling circuit as shown by Akiyama et al. to the Proebsting apparatus in order to lower cost by employing parts of first and second DAC's commonly (See Col. 2, Lines 33-36 in Akiyama et al. reference).

As to claim 4, Proebsting teaches a drive circuit, comprising: a plurality of digital-to-analog conversion circuit (See Fig. 1, items 106-1 to 106-n, See Col. 1, lines 38-49) each of which outputs an analog signal (See Fig. 5, items 404-409, Col. 4, Lines 1-30) corresponding to a digital gradation signal (See Fig. 4, item 410, Col. 4, Lines 30-34; and wherein each output terminal of the digital-to analog conversion circuit connects to a corresponding variable resistor circuit with a resistance value corresponding to a digital gradation signal lines (See Fig. 4-5, items 404,406,408,410, from Col. 4, Line 1 to Col.5, Line 20); wherein the sampling circuit comprises a plurality of switches each of which has an approximate same resistance value (See Fig. 4, items 404, 406, 408,Col. 4, Lines 26-30); wherein a divided voltage point of selected reference voltages is generated by a series resistance comprising a resistance value of the variable resistance circuit and resistance value of switches constituting the sampling circuit (See Fig. 4, items 404, 406, r, 408, Col. 4, Lines 1-34).

Proebsting does not teach a sampling circuit which selectively connects each output terminal of two of variable resistor circuits to a corresponding one of a plurality of signal lines.

Akiyama et al. teaches a sampling circuit which connects each output terminal of two of variable resistor circuits to a corresponding one of a plurality of signal lines (See

Fig. 8, items 113, 123, Col. 9, Lines 26-36); wherein the sampling circuit outputs a predetermined voltage by connecting an output voltage terminal of the plurality of digital-to-analog conversion circuits to one of signal lines (See Fig. 8, items 113, 123, Col. 9, Lines 26-36).

It would have been obvious to one of ordinary skill in the art at the time of invention to add a sampling circuit as shown by Akiyama et al. to the Proebsting apparatus in order to lower cost by employing parts of first and second DAC's commonly (See Col. 2, Lines 33-36 in Akiyama et al. reference).

As to claims 5-8, Proebsting teaches switching elements which conduct according to gradation signal as the resistors values corresponding to gradation circuit and resistance elements, connected in series with each other, as the resistors with resistance values corresponding to gradation signal (See Fig. 4-5, items 404,406,408,410, in description from Col. 4, Line 1 to Col.5, Line 20).

As to claims 9-12, Proebsting, Akiyama et al. and Minami et al. teach all limitations reflected in rejections of claims 1-4. The only difference between claims 1-4 and 9-12 positive and negative circuits.

Akiyama et al. teaches to generate negative and positive polarity D/A converters, and a switching block having plurality of switching circuits for receiving the negative and positive polarity analog video signals (See Figs. 8, 10, items 111, 121, 113, 123, from Col. 9, Line 3 to Col. 10, Line 15).

It would have been obvious to one of ordinary skill in the art at the time of invention to generate negative and positive polarity D/A converters, and a switching

block having plurality of switching circuits for receiving the negative and positive polarity analog video signals as shown by Akiyama et al. in the Proebsting apparatus to generate positive and negative analog driving signals in order to lower cost by employing parts of first and second DAC's commonly (See Col. 2, Lines 33-36 in Akiyama et al. reference).

As to claims 13-16, Proebsting teaches switching elements which conduct according to gradation signal as the resistors values corresponding to gradation circuit and resistance elements, connected in series with each other, as the resistors with resistance values corresponding to gradation signal (See Fig. 4-5, items 404,406,408,410, in description from Col. 4, Line 1 to Col.5, Line 20).

As to claims 25-32, 49-52, Proebsting teaching plurality of references voltages are fewer in numbers than the gradations of displayed images (See Figs. 3-5, items 300,302,206i, 400, 402, in description See from Col. 3, line 66 to Col. 4, Line9 and Lines 49-58).

As to claims 33-44, Proebsting teaching an image display apparatus with a drive circuit, wherein a plurality of signal lines for transmitting image signals and a plurality of scanning lines for transmitting scanning signals are formed in a matrix-like fashion in an image display area of a substrate, an lector-optical conversion element or liquid crystal which changes its light transmittance or emission intensity to an electrical signal is placed near each intersection of the signal lines and scanning lines or liquid crystals are sandwiched between substrate and another substrate, signal lines are

connected to drive circuit, and scanning line connected to a scanning circuit (See Fig.1, items 102-108, in description See Col. 1, Lines 5-65).

2. Claims 17-20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Proebsting, Akiyama et al. as applied to claim 2, 4, 10, 12 above, and further in view of Jeong (US Patent No. 6, 335, 721 B1).

As to claims 17-18, Proebsting, Akiyama et al. do not show among the groups of the switching elements belonging to sampling circuit, a pair of switching elements connected to the same signal line conduct simultaneously in response to signal line selection signal.

Jeong teaches among the groups of the switching elements belonging to sampling circuit, a pair of switching elements connected to the same signal line conduct simultaneously in response to signal line selection signal (See Fig. 3, items N-EN, Vdd1, in description See Col. 2, Lines 24-34).

It would have been obvious to one of ordinary skill in the art at the time of invention to use the groups of the switching elements belonging to sampling circuit, a pair of switching elements connected to the same signal line conduct simultaneously in response to signal line selection signal as shown by Jeong in the Proebsting, Akiyama et al. apparatus in order to reduce power consumption.

As to claims 19-20, Proebsting, Akiyama et al. do not show among the groups of the positive switching elements belonging to positive sampling circuit, a pair of switching elements connected to the same signal line conduct simultaneously in response to

positive signal line selection signal and among the groups of the negative switching elements belonging to negative sampling circuit, a pair of switching elements connected to the same signal line conduct simultaneously in response to negative signal line selection signal.

Jeong teaches among the groups of the positive switching elements belonging to positive sampling circuit, a pair of switching elements connected to the same signal line conduct simultaneously in response to positive signal line selection signal and among the groups of the negative switching elements belonging to negative sampling circuit, a pair of switching elements connected to the same signal line conduct simultaneously in response to negative signal line selection signal (See Figs. 1-3, items Channel, Row, N_EN, P_EN, OUTPUT, in description See from Col. 1, Line 16 to Col. 2, Line 34).

It would have been obvious to one of ordinary skill in the art at the time of invention to use the groups of the positive switching elements belonging to positive sampling circuit, a pair of switching elements connected to the same signal line conduct simultaneously in response to positive signal line selection signal and among the groups of the negative switching elements belonging to negative sampling circuit, a pair of switching elements connected to the same signal line conduct simultaneously in response to negative signal line selection signal as shown by Jeong in the Proebsting, Akiyama et al. apparatus in order to reduce power consumption.

3. Claims 21-24, 45-48 are rejected under 35 U.S.C. 103(a) as being unpatentable over Proebsting, Akiyama et al. as aforementioned in claims 2,4,8,10,41-44 in view Nakamura et al. (US Patent no. 6,411,273 B1)

Proebsting, Akiyama et al. do not show switching elements are comprise thin-film transistors.

Nakamura et al. teaches thin-film transistors as switching elements (See Fig. 14, items 117,117A, 118a, in description See Col. 45, Lines 11-16).

It would have been obvious to one of ordinary skill in the art at the time of invention to use thin-film transistors as shown by Nakamura et al. in the Proebsting, Akiyama et al. apparatus in order to reduce power consumption (See Col. 2, Lines 54-59 in Nakamura et al. reference).

Response to Arguments

4. Applicant's arguments filed on 07.11.05 have been fully considered but they are not persuasive.

On page 20, 1st paragraph of the Remarks Applicant's stated that limitation of independent claims: "a sampling circuit which selectively connects each output terminal of two of the digital-to analog conversion circuits to signal lines" not teach by Proebsting and Akiyama. However, Akiyama exactly teaches this limitation: a sampling circuit (See Fig.8, items 113, 123) which selectively connects each output terminal of two of the digital-to analog conversion circuits (See Fig.8, items 11, 12) to signal lines (See Fig. 8, item ANALOG SIGNAL OUTPUT, Col. 9, Lines 26-36).

In the same paragraph and up to 3rd paragraph on page 21, Applicant's stated that current path of the claimed invention is different from the current path of Proebsting and Akiyama, referring to Fig. 2 and specification. However, Applicant's argue limitations that are not in the claims. The Specification is not the measure of invention. Therefore, limitations contained therein can not be read into the claims for purpose of avoiding the prior art. In re Sporck, 55 CCPA 743, 386 F.2d 924, 155 USPQ 687 (1968).

Telephone inquire

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Leonid Shapiro whose telephone number is 571-272-7683. The examiner can normally be reached on 8 a.m. to 5 p.m..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Bipin Shalwala can be reached on 571-272-7681. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

LS
09.18.05

VIJAY SHANKAR
PRIMARY EXAMINER